MSKSEMI















ESD

TVS

TSS

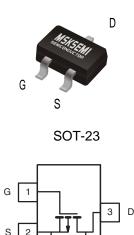
MOV

GDT

PLED

Broduct data sheet





Features

- $-20V, -5.5A, RDS(ON) = 25m\Omega@VGS = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-12V	25m Ω	-5.5A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-12	V
V _{GS}	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T _C =25°C)	-5.5	Α
I _D	Drain Current – Continuous (T _C =100°C)	-3.5	Α
I _{DM}	Drain Current – Pulsed ¹	-21.2	Α
D	Power Dissipation (T _C =25°C)	1.56	W
P _D	Power Dissipation – Derate above 25°C	0.012	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
R _{0JA}	Thermal Resistance Junction to ambient		80	°C/W

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-12			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.02		V/°C
	Drain Source Leakage Current	V _{DS} =-20V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-16V , V _{GS} =0V , T _J =125°C			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±12V , V _{DS} =0V			±100	nA

On Characteristics

		V _{GS} =-4.5V , I _D =-4A		25	35	mΩ
R _{DS(ON)}	Static Drain-Source On-Resistance	V_{GS} =-2.5 V , I_D =-3 A		35	50	1112.2
$V_{GS(th)}$	Gate Threshold Voltage	V -V I - 2500A	-0.3	-0.6	-1	V
$\triangle V_{\text{GS(th)}}$	V _{GS(th)} Temperature Coefficient	-V _{GS} =V _{DS} , I _D =-250uA		2		mV/°C
gfs	Forward Transconductance	V _{DS} =-12V , I _S =-3A		8.4		S

Dynamic and switching Characteristics

•	•			
Qg	Total Gate Charge ^{2, 3}		 16.1	
Q_gs	Gate-Source Charge ^{2, 3}	V_{DS} =-10V , V_{GS} =-4.5V , I_{D} =-4A	 1.8	 nC
Q_gd	Gate-Drain Charge ^{2, 3}		 3.8	
$T_{d(on)}$	Turn-On Delay Time ^{2, 3}		 8.2	
Tr	Rise Time ^{2, 3}	V_{DD} =-10V , V_{GS} =-4.5V , R_{G} =25 Ω	 30	 nS
$T_{d(off)} \\$	Turn-Off Delay Time ^{2, 3}	I _D =-1A	 71.1	 113
T_f	Fall Time ^{2, 3}		 19.8	
C_{iss}	Input Capacitance		 1440	
C _{oss}	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , F=1MHz	 155	 pF
C _{rss}	Reverse Transfer Capacitance		 115	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V =V =0V Force Current			-5.5	Α
I _{SM}	Pulsed Source Current	V _G =V _D =0V , Force Current			-21.2	Α
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =25°C			-1.2	V

Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%.$
- 3. Essentially independent of operating temperature.



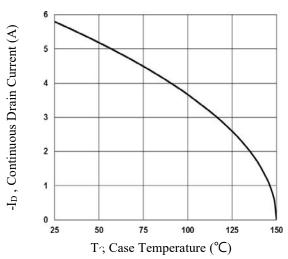


Fig.1 Continuous Drain Current vs. Tc

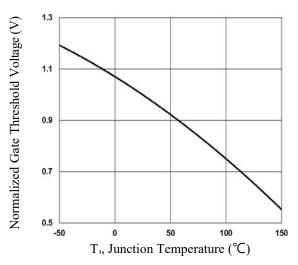


Fig.3 Normalized V_{th} vs. T_J

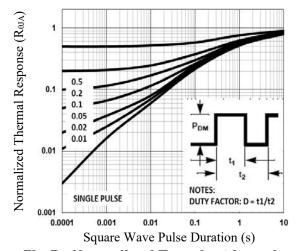


Fig.5 Normalized Transient Impedance

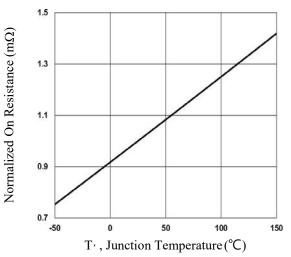


Fig.2 Normalized RDSON vs. TJ

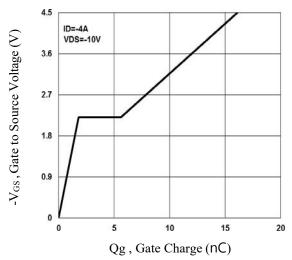


Fig.4 Gate Charge Waveform

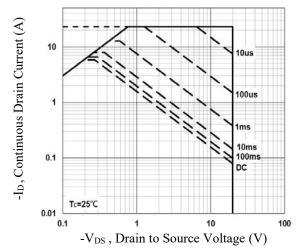


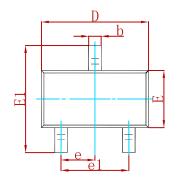
Fig.6 Maximum Safe Operation Area

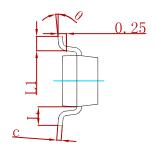


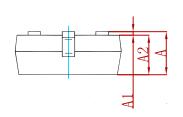






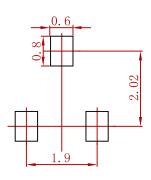






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550	REF	0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2333DDS-T1-GE3-MS	SOT-23	3000



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